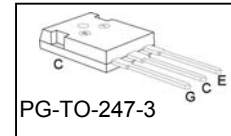
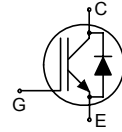


## Reverse Conducting IGBT with monolithic body diode

**Features:**

- Powerful monolithic Body Diode with very low forward voltage
- Body diode clamps negative voltages
- TrenchStop® and Fieldstop technology for 1200 V applications offers :
  - very tight parameter distribution
  - high ruggedness, temperature stable behavior
- NPT technology offers easy parallel switching capability due to positive temperature coefficient in  $V_{CE(sat)}$
- Low EMI
- Qualified according to JEDEC<sup>1</sup> for target applications
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models : <http://www.infineon.com/igbt/>


**Applications:**

- Inductive Cooking
- Soft Switching Applications

Type	$V_{CE}$	$I_C$	$V_{CE(sat), T_j=25^\circ C}$	$T_{j,max}$	Marking	Package
IHW30N120R2	1200V	30A	1.65V	175°C	H30R1202	PG-TO-247-3

**Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CE}$	1200	V
DC collector current	$I_C$	60	A
$T_C = 25^\circ C$		30	
$T_C = 100^\circ C$			
Pulsed collector current, $t_p$ limited by $T_{j,max}$	$I_{C,puls}$	90	
Turn off safe operating area ( $V_{CE} \leq 1200V, T_j \leq 175^\circ C$ )	-	90	
Diode forward current	$I_F$	60	
$T_C = 25^\circ C$		30	
$T_C = 100^\circ C$			
Diode pulsed current, $t_p$ limited by $T_{j,max}$	$I_{F,puls}$	90	
Diode surge non repetitive current, $t_p$ limited by $T_{j,max}$	$I_{FSM}$	50	
$T_C = 25^\circ C, t_p = 10ms$ , sine halfwave		130	
$T_C = 25^\circ C, t_p \leq 2.5\mu s$ , sine halfwave		120	
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Transient Gate-emitter voltage ( $t_p < 5ms$ )		$\pm 25$	
Power dissipation $T_C = 25^\circ C$	$P_{tot}$	390	W
Operating junction temperature	$T_j$	-40...+175	°C
Storage temperature	$T_{stg}$	-55...+175	
Soldering temperature, 1.6mm (0.063 in.) from case for 10s	-	260	

<sup>1</sup> J-STD-020 and JESD-022

### Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
<b>Characteristic</b>				
IGBT thermal resistance, junction – case	$R_{thJC}$		0.38	K/W
Diode thermal resistance, junction – case	$R_{thJCD}$		0.37	
Thermal resistance, junction – ambient	$R_{thJA}$		40	

### Electrical Characteristic, at $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	max.	
<b>Static Characteristic</b>						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=1mA$	1200	-	-	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE} = 15V, I_C=30A$ $T_j=25\text{ }^\circ\text{C}$ $T_j=125\text{ }^\circ\text{C}$ $T_j=175\text{ }^\circ\text{C}$	-	1.65	1.8	
Diode forward voltage	$V_F$	$V_{GE}=0V, I_F=30A$ $T_j=25\text{ }^\circ\text{C}$ $T_j=125\text{ }^\circ\text{C}$ $T_j=175\text{ }^\circ\text{C}$	-	1.55	1.8	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=0.7mA, V_{CE}=V_{GE}$	5.1	5.8	6.4	
Zero gate voltage collector current	$I_{CES}$	$V_{CE}=1200V, V_{GE}=0V$ $T_j=25\text{ }^\circ\text{C}$ $T_j=175\text{ }^\circ\text{C}$	-	-	5 2500	$\mu\text{A}$
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0V, V_{GE}=20V$	-	-	100	nA
Transconductance	$g_{fs}$	$V_{CE}=20V, I_C=30A$	-	19.7	-	S
Integrated gate resistor	$R_{Gint}$			none		$\Omega$

### Dynamic Characteristic

Input capacitance	$C_{iss}$	$V_{CE}=25V,$	-	2589	-	pF
Output capacitance	$C_{oss}$	$V_{GE}=0V,$	-	77	-	
Reverse transfer capacitance	$C_{riss}$	$f=1MHz$	-	62	-	
Gate charge	$Q_{Gate}$	$V_{CC}=960V, I_C=30A$ $V_{GE}=15V$	-	198	-	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	$L_E$		-	13	-	nH

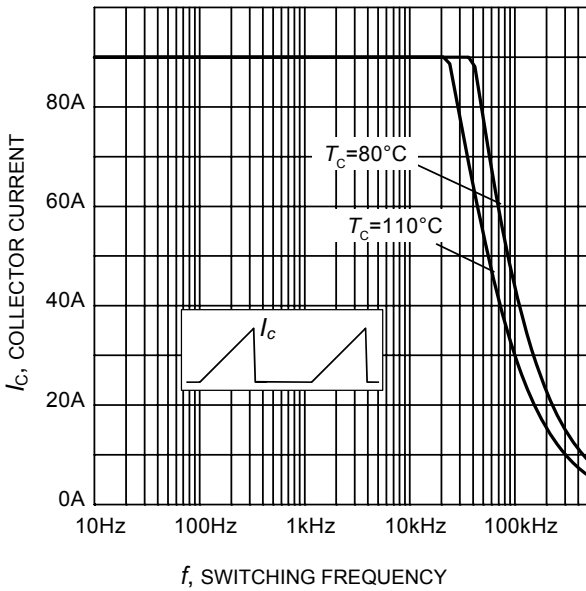
### Switching Characteristic, Inductive Load, at $T_j=25^\circ C$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	Max.	
<b>IGBT Characteristic</b>						
Turn-off delay time	$t_{d(off)}$	$T_j=25^\circ C,$	-	792	-	ns
Fall time	$t_f$	$V_{CC}=600V, I_C=30A,$	-	33	-	
Turn-on energy	$E_{on}$	$V_{GE}=0 / 15V,$	-	-	-	mJ
Turn-off energy	$E_{off}$	$R_G=28\Omega,$	-	2.4	-	
Total switching energy	$E_{ts}$	$L_\sigma^{2)}=180nH,$ $C_\sigma^{2)}=39pF$	-	2.4	-	

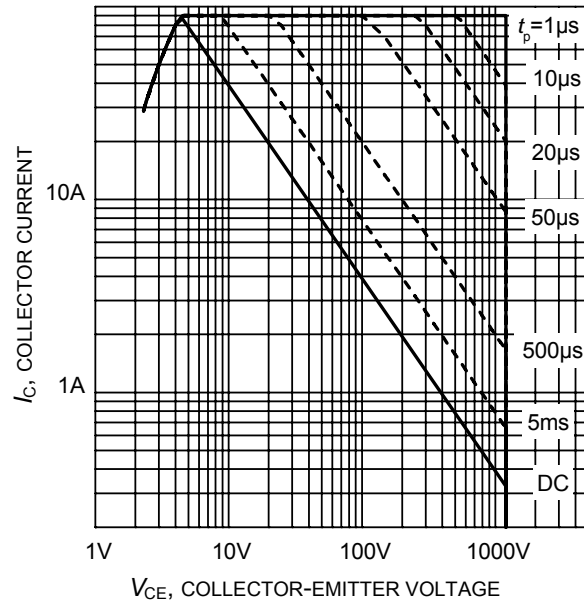
### Switching Characteristic, Inductive Load, at $T_j=175^\circ C$

Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	Max.	
<b>IGBT Characteristic</b>						
Turn-off delay time	$t_{d(off)}$	$T_j=175^\circ C$	-	860	-	ns
Fall time	$t_f$	$V_{CC}=600V, I_C=30A,$	-	40	-	
Turn-on energy	$E_{on}$	$V_{GE}=0 / 15V,$	-	-	-	mJ
Turn-off energy	$E_{off}$	$R_G=28\Omega,$	-	3.1	-	
Total switching energy	$E_{ts}$	$L_\sigma=180nH^{2)},$ $C_\sigma=39pF^{2)}$	-	3.1	-	

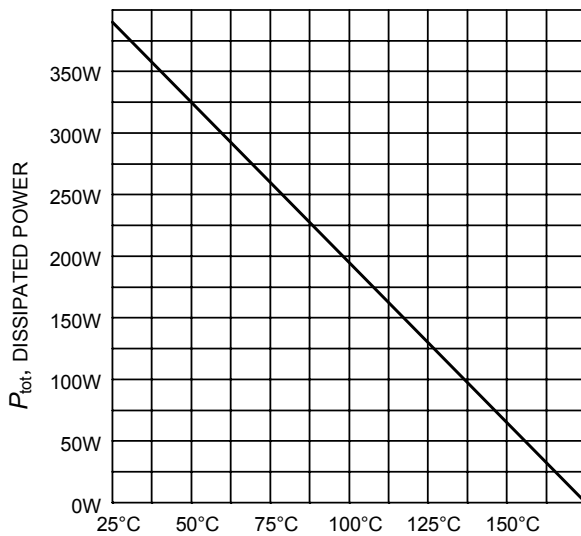
<sup>2)</sup> Leakage inductance  $L_\sigma$  and Stray capacity  $C_\sigma$  due to dynamic test circuit in Figure E.



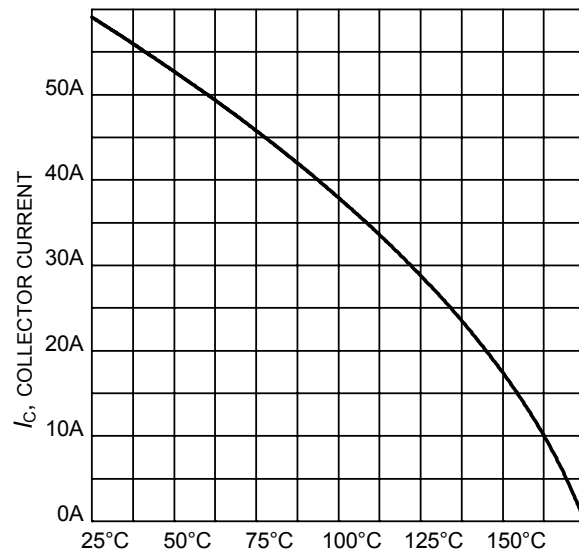
**Figure 1. Collector current as a function of switching frequency for hard switching (turn-off)**  
 ( $T_j \leq 175^\circ\text{C}$ ,  $D = 0.5$ ,  $V_{CE} = 600\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  $R_G = 28\Omega$ )



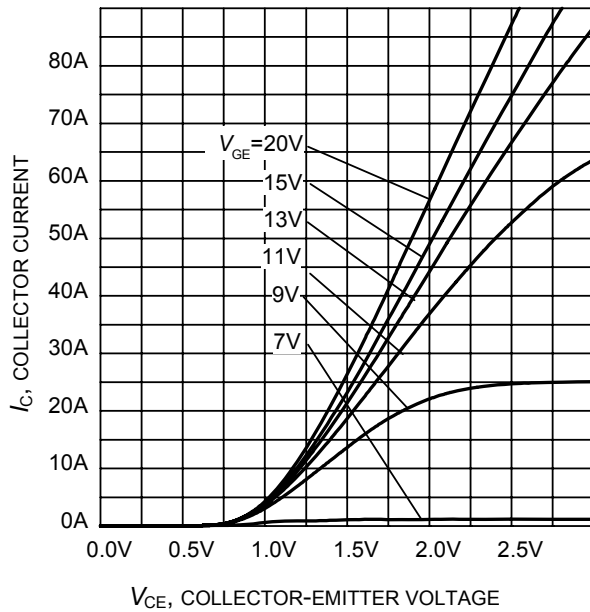
**Figure 2. IGBT Safe operating area**  
 ( $D = 0$ ,  $T_C = 25^\circ\text{C}$ ,  $T_j \leq 175^\circ\text{C}$ ;  $V_{GE} = 15\text{V}$ )



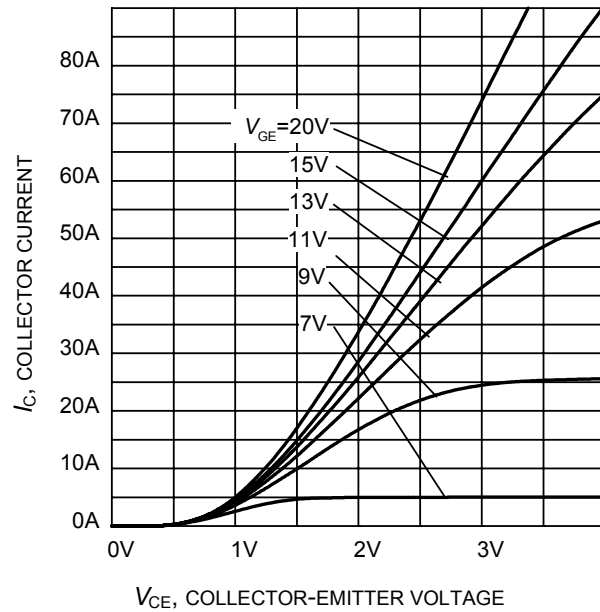
**Figure 3. Power dissipation as a function of case temperature**  
 ( $T_j \leq 175^\circ\text{C}$ )



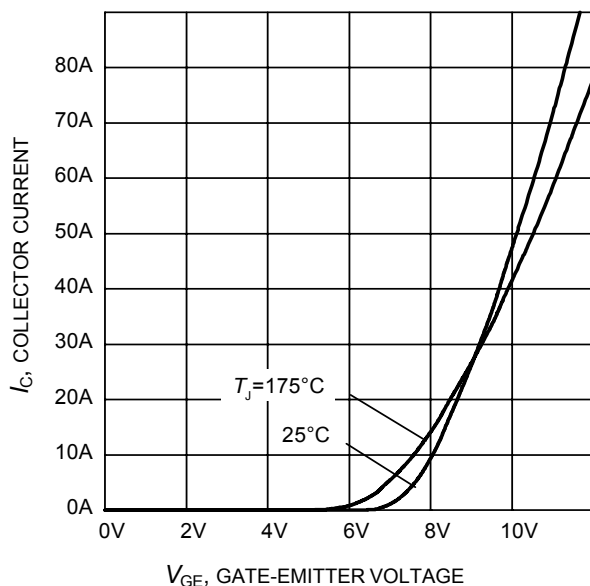
**Figure 4. DC Collector current as a function of case temperature**  
 ( $V_{GE} \geq 15\text{V}$ ,  $T_j \leq 175^\circ\text{C}$ )



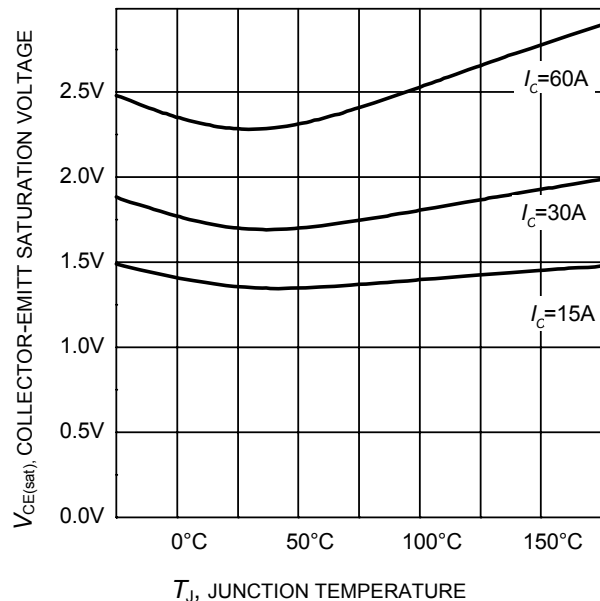
**Figure 5. Typical output characteristic**  
( $T_j = 25^\circ\text{C}$ )



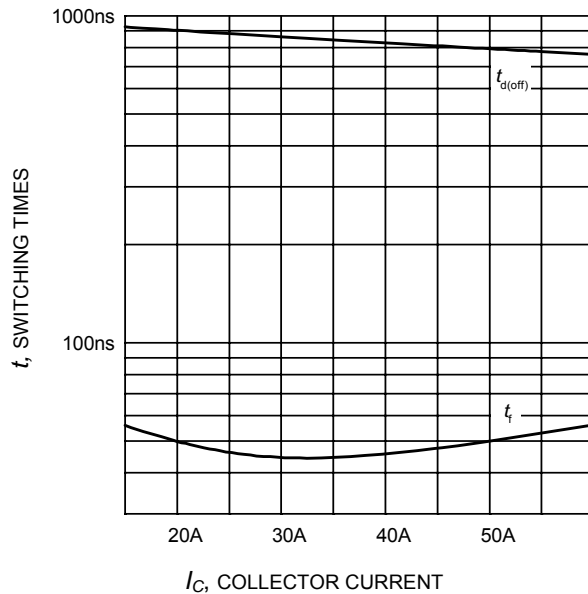
**Figure 6. Typical output characteristic**  
( $T_j = 175^\circ\text{C}$ )



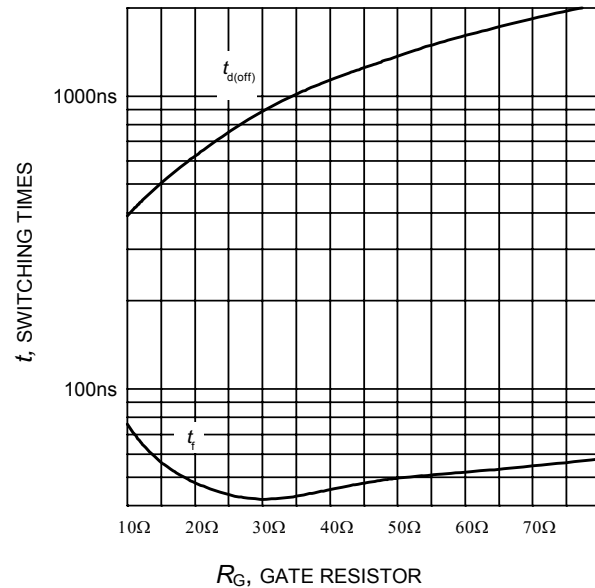
**Figure 7. Typical transfer characteristic**  
( $V_{CE} = 20\text{V}$ )



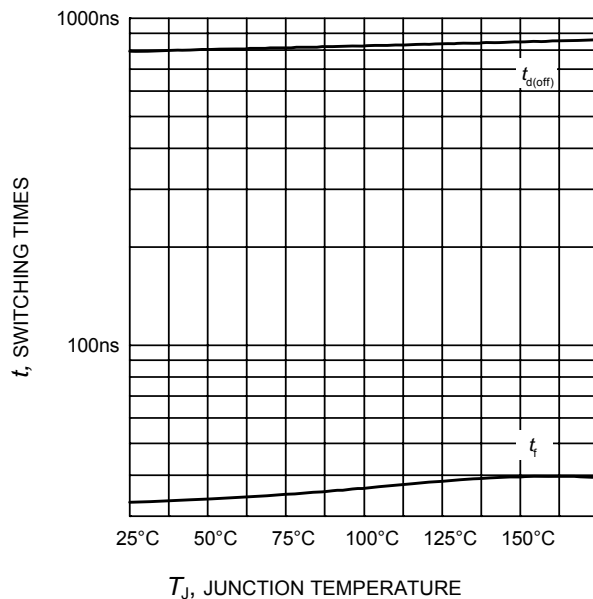
**Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature**  
( $V_{GE} = 15\text{V}$ )



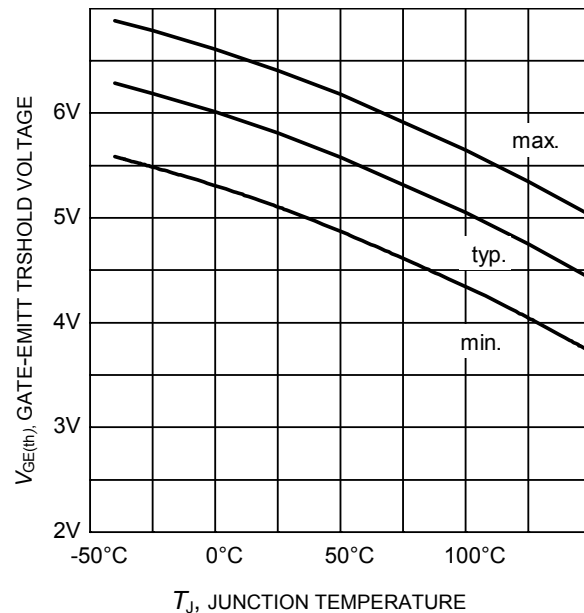
**Figure 9. Typical switching times as a function of collector current**  
(inductive load,  $T_J=175^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $R_G=28\Omega$ , Dynamic test circuit in Figure E)



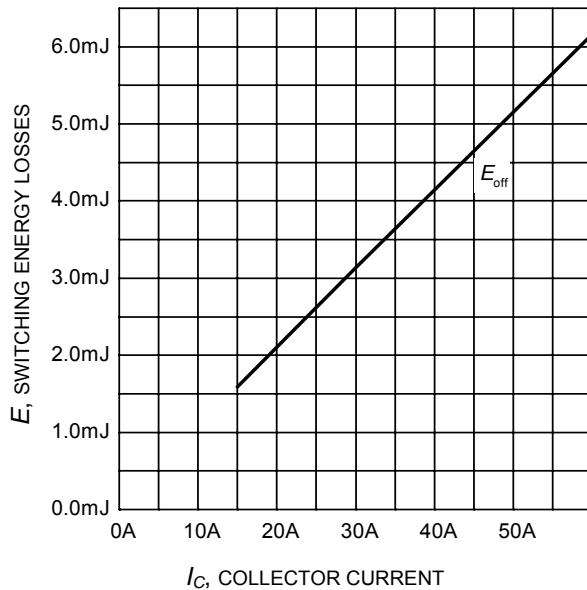
**Figure 10. Typical switching times as a function of gate resistor**  
(inductive load,  $T_J=175^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $I_C=30\text{A}$ , Dynamic test circuit in Figure E)



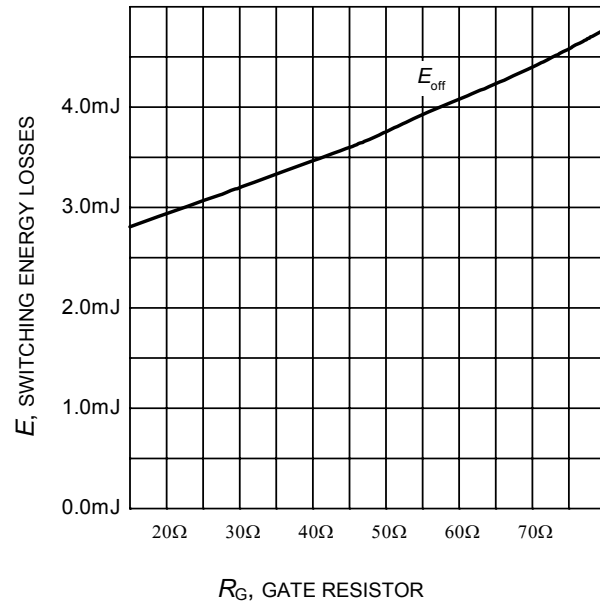
**Figure 11. Typical switching times as a function of junction temperature**  
(inductive load,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $I_C=30\text{A}$ ,  $R_G=28\Omega$ , Dynamic test circuit in Figure E)



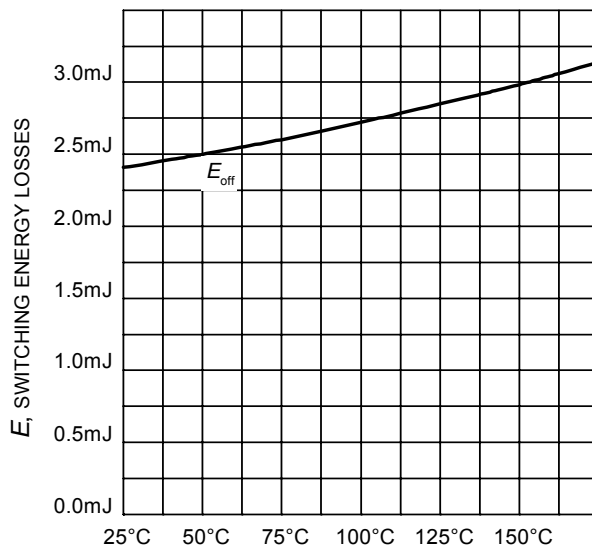
**Figure 12. Gate-emitter threshold voltage as a function of junction temperature**  
( $I_C = 0.7\text{mA}$ )



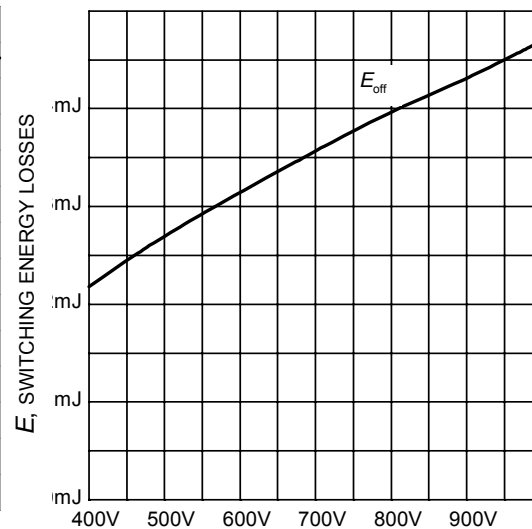
**Figure 13. Typical turn-off energy as a function of collector current**  
 (inductive load,  $T_J=175^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $R_G=28\Omega$ , Dynamic test circuit in Figure E)



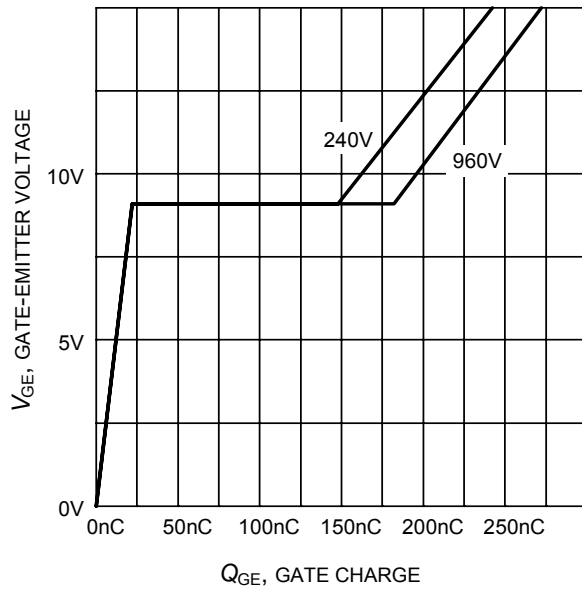
**Figure 14. Typical turn-off energy as a function of gate resistor**  
 (inductive load,  $T_J=175^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $I_C=30\text{A}$ , Dynamic test circuit in Figure E)



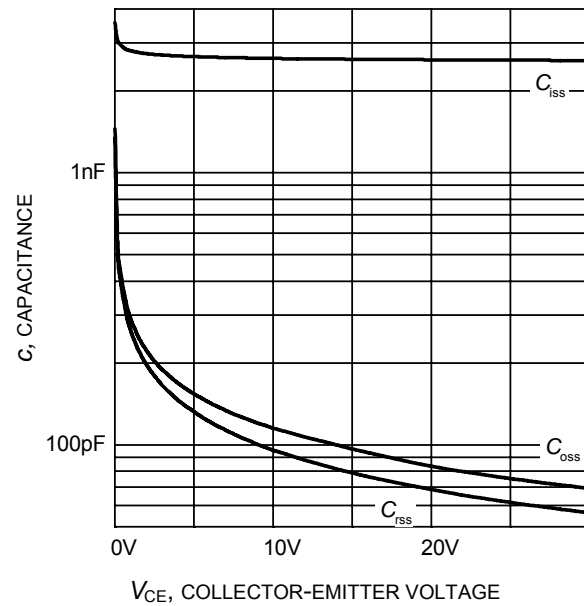
**Figure 15. Typical turn-off energy as a function of junction temperature**  
 (inductive load,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $I_C=30\text{A}$ ,  $R_G=28\Omega$ , Dynamic test circuit in Figure E)



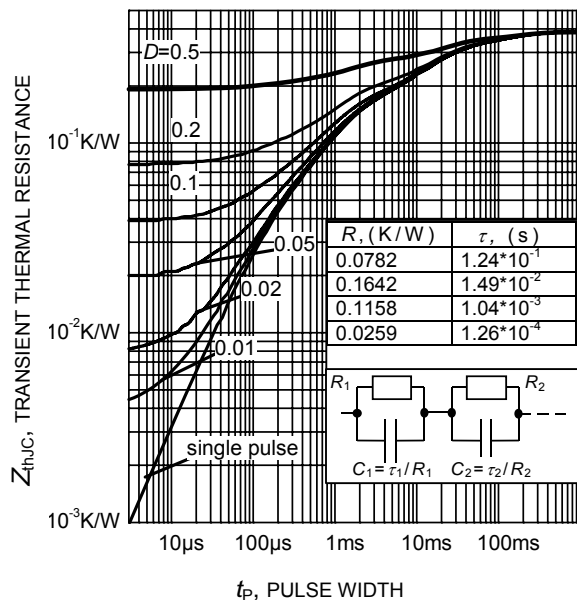
**Figure 16. Typical turn-off energy as a function of collector emitter voltage**  
 (inductive load,  $T_J=175^\circ\text{C}$ ,  $V_{GE}=0/15\text{V}$ ,  $I_C=30\text{A}$ ,  $R_G=28\Omega$ , Dynamic test circuit in Figure E)



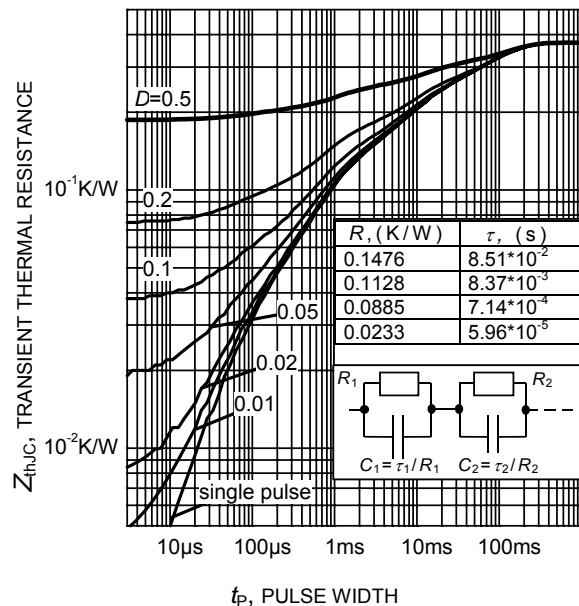
**Figure 17. Typical gate charge**  
( $I_C=30\text{ A}$ )



**Figure 18. Typical capacitance as a function of collector-emitter voltage**  
( $V_{GE}=0\text{V}$ ,  $f = 1\text{ MHz}$ )

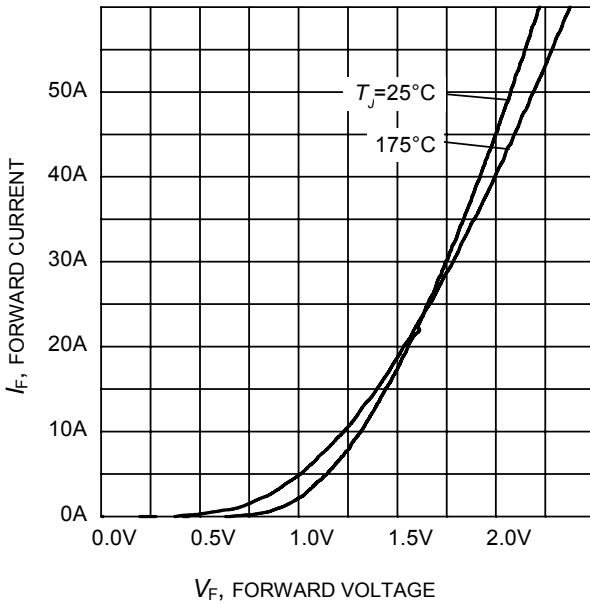


**Figure 19. IGBT transient thermal resistance**  
( $D = t_p / T$ )

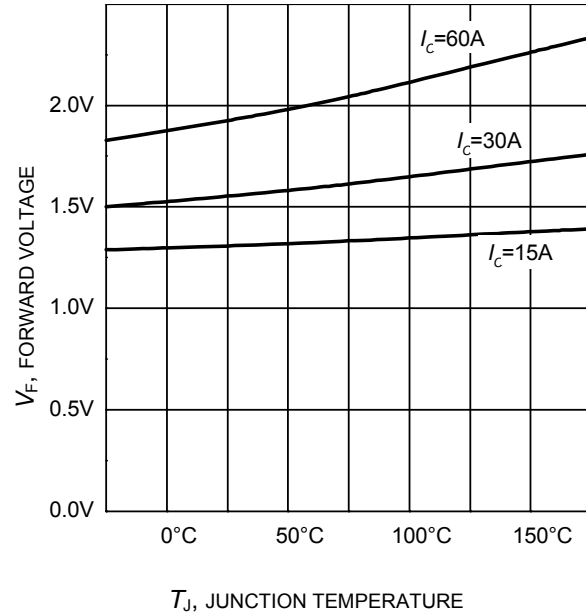


**Figure 20. Diode transient thermal impedance as a function of pulse width**  
( $D = t_p / T$ )

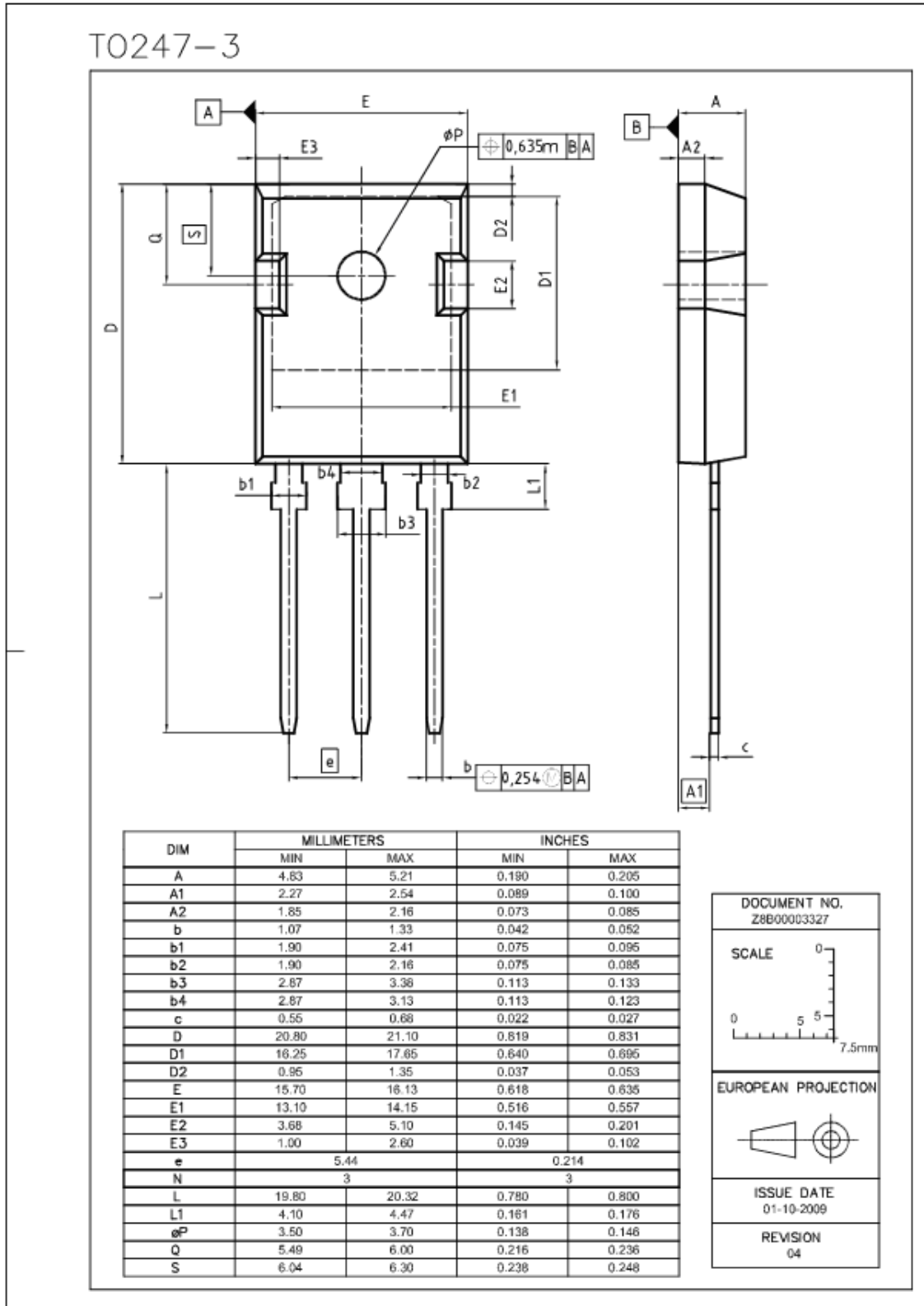




**Figure 21. Typical diode forward current as a function of forward voltage**



**Figure 22. Typical diode forward voltage as a function of junction temperature**



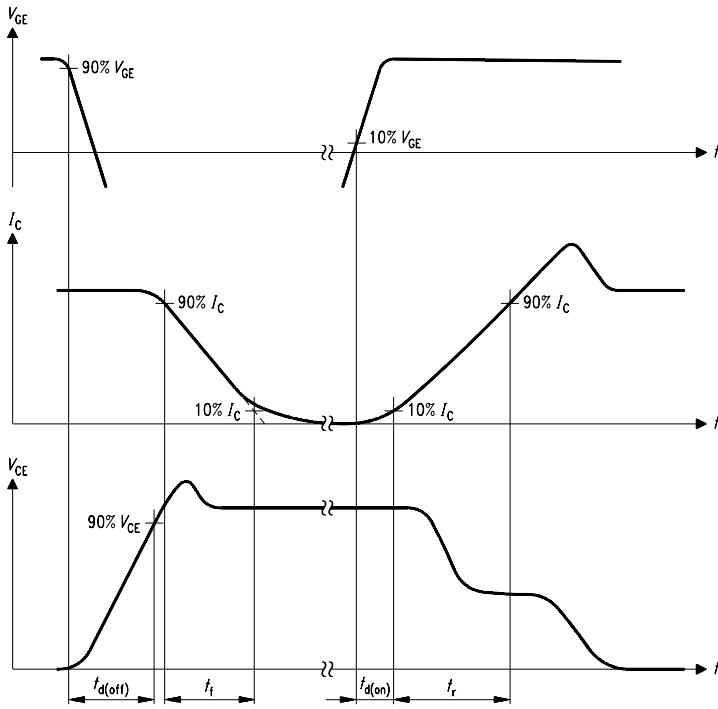


Figure A. Definition of switching times

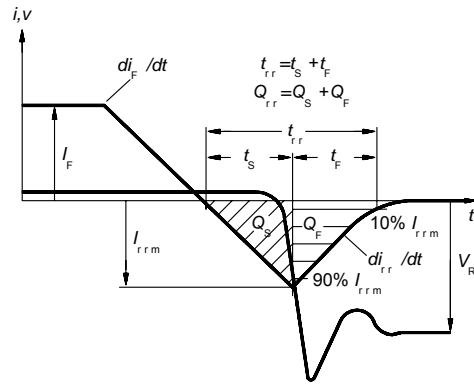


Figure C. Definition of diodes switching characteristics

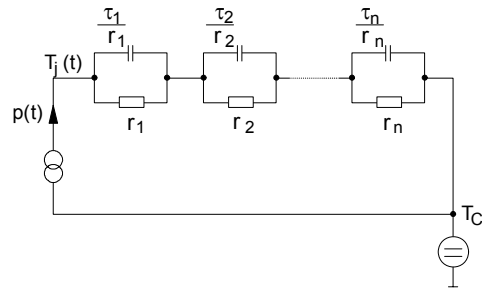


Figure D. Thermal equivalent circuit

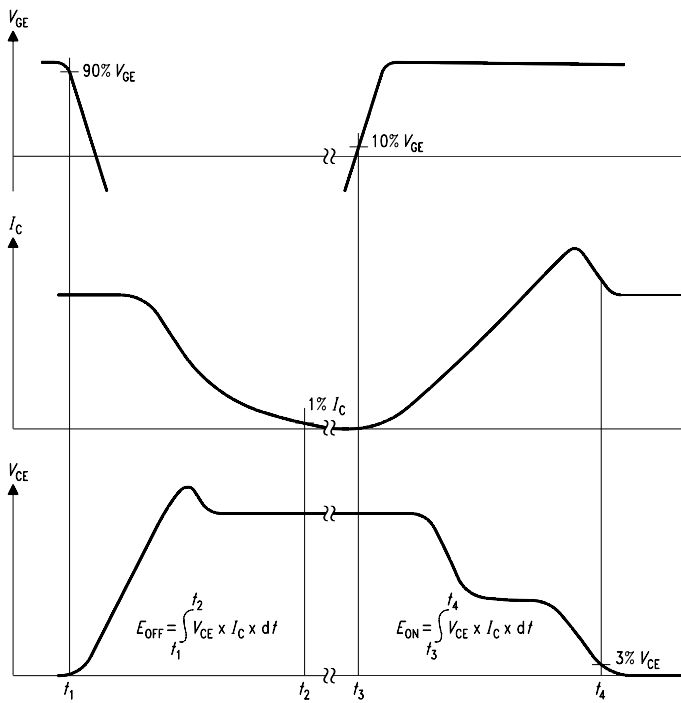


Figure B. Definition of switching losses

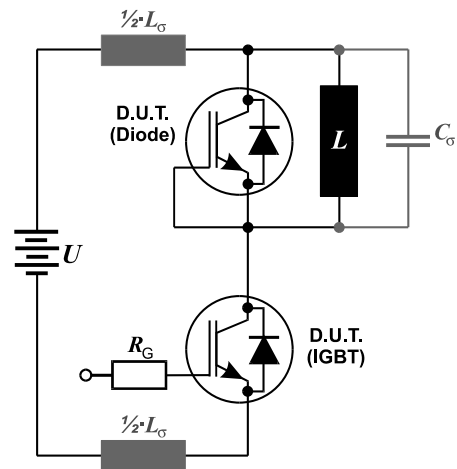


Figure E. Dynamic test circuit  
Leakage inductance  $L_\sigma$  and Stray capacity  $C_\sigma$

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